

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Manoocher Birang et al                      Art Unit : Unassigned  
Serial No. : Unassigned                                  Examiner : Unknown  
Filed : Herewith  
Title : POLISHING PAD FOR IN-SITU ENDPOINT DETECTION

MAIL STOP PATENT APPLICATION  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicant submits the references listed on the attached form PTO-1449.

Under 35 USC §120, this application is a continuation application of U.S. Application Serial No.09/672,532, filed September 28, 2000, which is a divisional of U.S. Application Serial No. 09/028,412, filed February 24, 1998, which is a continuation of U.S. Application Serial No. 08/979015, filed November 26, 1997, which is a continuation of U.S. Application Serial No. 08/413,982, filed March 28, 1995. The disclosure of each of the prior applications is considered part of (and is incorporated by reference in) the disclosure of this application.

The following references were submitted to and/or cited by the Office in the prior application and, therefore, are not provided in this application:

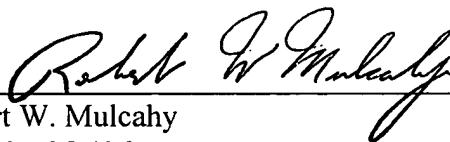
Desig. IDs:

AA-AJJJ

This statement is being filed with the application. Accordingly, only copies of foreign patent documents and non-patent literature are enclosed. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: November 25, 2003



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Substitute Form PTO-1449 (Modified)		U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 05542-146009	Application No. Unassigned
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)  (37 CFR §1.98(b))		Applicant Manoocher Birang et al		
		Filing Date Herewith	Group Art Unit Unassigned	

<b>U.S. Patent Documents</b>							
Examiner Initial	Desig. ID	Document Number	Publication/ Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	4,272,924	06/16/81	Masuko, et al.			
	AB	4,328,068	05/04/82	Curtis			
	AC	4,512,847	04/23/85	Brunsch, et al.			
	AD	4,793,895	12/27/88	Kaanta et al.			
	AE	4,948,259	08/14/90	Enke et al.			
	AF	4,954,142	09/04/90	Carr, et al.			
	AG	5,036,015	07/1991	Sandhu et al.			
	AH	5,081,421	01/14/92	Miller, et al.			
	AI	5,097,430	03/17/92	Birang			
	AJ	5,132,617	07/21/92	Leach, et al.			
	AK	5,196,353	03/23/93	Sandhu, et al.			
	AL	5,213,655	05/25/93	Leach et al.			
	AM	5,219,787	06/15/93	Carey et al.			
	AN	5,234,868	08/10/93	Cote			
	AO	5,240,552	08/31/93	Yu et al.			
	AP	5,242,524	09/07/93	Leach et al.			
	AQ	5,257,478	11/02/93	Hyde et al.			
	AR	5,265,378	11/30/93	Rostoker			
	AS	5,294,289	03/15/94	Heinz et al.			
	AT	5,308,438	05/03/94	Cote et al.			
	AU	5,321,304	06/14/94	Rostoker			
	AV	5,332,467	07/26/94	Sune et al.			
	AW	5,337,015	08/09/94	Lustig, et al.			
	AX	5,395,801	03/07/95	Doan, et al.			
	AY	5,413,941	05/1995	Koos et al.			
	AZ	5,433,651	7/1995	Lustig et al.			
	AAA	5,489,233	02/1996	Cook et al.			

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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<b>U.S. Patent Documents</b>							
Examiner Initial	Desig. ID	Document Number	Publication/Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
	BA	5,605,760	02/25/97	Roberts			
	BB	5,609,511	03/11/97	Moriyama, et al.			
	BC	5,672,091	09/30/97	Takahashi et al.			
	BD	5,893,796	04/1999	Birang et al.			
	BE	5,949,927	09/1999	Tang			
	BF	6,045,439	04/2000	Birang et al.			
	BG	6,146,248	11/2000	Jairath et al.			
	BH	US-2001/0036805	05/2001	Birang et al.			

<b>Foreign Patent Documents or Published Foreign Patent Applications</b>							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation
							Yes No
	BI	CA 625,573	08/15/61	Canada Patent			
	BJ	EP 0 738 561 A1	10/1996	Europe			
	BK	EP 468 897	01/29/92	Europe			
	BL	EP-A-0 352 740	01/90	Europe			
	BM	EP-A-0 633 265	07/19/95	Europe			
	BN	FR-A-1 075 634	10/54	France			
	BO	JP 2-222533	09/05/90	Japan Abstract			
	BP	JP 259938	06/10/89	Japan Abstract			
	BQ	JP 3-234467	10/18/91	Japanese Patent Application			
	BR	JP 5-138531	06/01/93	Japan Abstract			
	BS	JP 5-309558	02/1993	Japan			
	BT	JP 58-4353	01/11/83	Japan			
	BU	JP 59-74635	04/27/84	Japan Abstract			
	BV	JP 61-164773	07/25/86	Japan Abstract			
	BW	JP 62-190728	08/20/87	Japan Abstract			

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<b>Foreign Patent Documents or Published Foreign Patent Applications</b>							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation Yes      No
	CA	JP 62-211927	09/07/87	Japan Abstract			
	CB	JP 62-283678	09/12/87	Japan Abstract			
	CC	JP 63-256344	10/24/88	Japan Abstract			
	CD	JP 7-052032	02/1995	Japan			
	CE	WO 93/20976	10/1993	WIPO			

<b>Other Documents (include Author, Title, Date, and Place of Publication)</b>		
Examiner Initial	Desig. ID	Document
	CF	Hench, "In situ real-time ellipsometry for film thickness measurement and control," J. Vac. Sci. Technol. A. Vol. 10, No. 4:934-938 (Jul/Aug. 1992).
	CG	Sautter, et al., "Development Process Control and Optimization Utilizing an End Point Monitor," SPIE Vol. 1087:312-321 (1989).
	CH	Jurczyk, et al., "Process Detection System," IBM Technical Disclosure Bulletin, Vol. 18 No. 6:1867-1870 (November 1975).
	CI	Anonymous, "End-Point Detection of Oxide Polishing and Planarization of Semiconductor Devices," Research Disclosure, No. 340 (August 1992).
	CJ	Rodel, "Wafer Mounting Assemblies and Materials", ©1992 Rodel, Scottsdale, Arizona.
	CK	Carotta, et al., "Effect of Thickness and Surface Treatment on Silicon Water Reflectance," Solar Energy Materials and Solar Cells 27: 265-272 (1992).
	CL	Rodel, "Glass Polishing Pads", January 1993, Scottsdale, Arizona

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